

Part 2: Process Fundamental Technology

Real men own fabs.
W.J. Saunders III, Chairman and CEO of Advanced Micro Devices Inc.

Building a new fab is like playing Russian roulette. When you build a fab, you hold the gun to your head, pull the trigger and wait three years to see if you're dead.
Unnamed IC company executive. (Integrated Circuit Design, September 1996)

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 1

Outline

- CMOS Processing
 - Wafer Production
 - CMOS Process Outline
 - Photolithography
 - Material Deposition & Removal
 - Oxide Growth & Removal
- Layout Design
 - Layer map
 - Layout examples
 - Stick diagrams
- Design Rules
 - Only very briefly

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 2

Course Material for 02-Process Chapter 2, 2nd ed.

P = primair, I = illustratie, O = overslaan

P	2.1	Introduction	36
P	2.2-2.2.2	Manufacturing CMOS Integrated Circuits	36-41
P	2.2.3	Some Recurring Process Steps	41-42
P	2.2.4	Simplified CMOS Process Flow	42-44
I	2.3	Design Rules	47-50
I	2.4	Packaging Integrated Circuits	51-61
I	2.5	Perspective - Trends in Process Technology	61-64
P	2.6	Summary	64
I	Insert A	IC Layout	67-71

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 3

CMOS Processing

- Overview
- Photolithography
- Material Deposition & Removal
- Oxide Growth & Removal

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 4

IC Technology





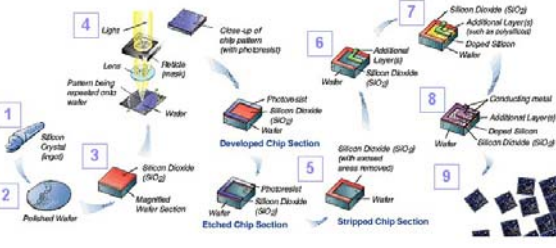

- cleaning
- deposition
- apply photoresist
- exposure
- development
- etching
- remove resist



Multiple cycles, 100's STEPS in total

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 5


Another Overview of Semiconductor Processing



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 6

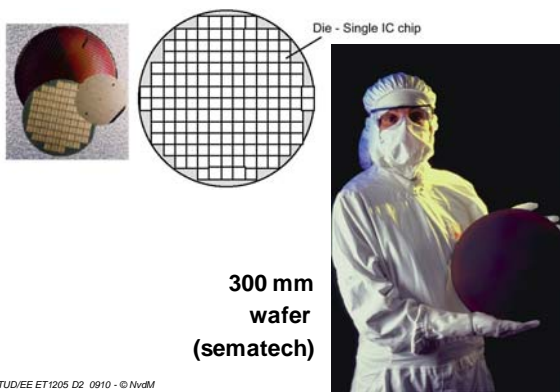
Wafer Processing – Czochralski Method

- Start with crucible of molten silicon ($\approx 1425^\circ\text{C}$)
- Insert crystal **seed** in melt
- Slowly rotate/raise seed to form single crystal **boule**
- After cooling, slice boule into **wafers** & polish



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 7

Wafer Structure



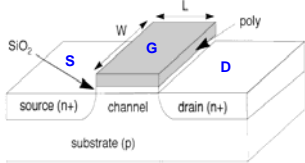
300 mm wafer (sematech)

TUD/EE ET1205 D2 0910 - © NvdM

CMOS Process Outline

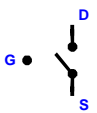
TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 9

MOS Transistor



Position of switch depends on gate to source voltage

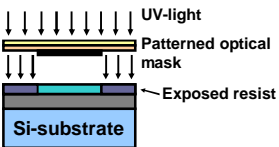
V_{GS}	NMOS	PMOS
hi	closed	open
lo	open	closed



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 10

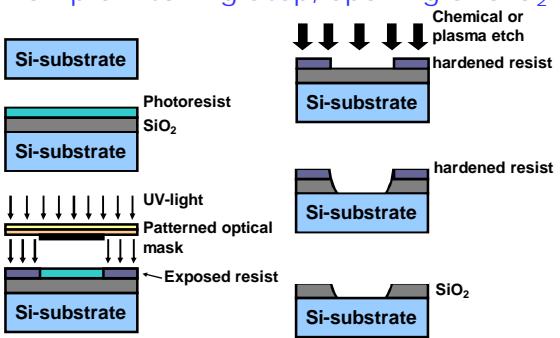
How Patterns on a Chip are Created

- Basic Principle: **Photolithography**
 - Like **projecting an image** through a photographic negative (or positive)
- Coat wafer with **Photoresist**
- Shine **UV light** through glass mask
- **Develop**: dunk in acid to remove exposed areas ("pos.") or unexposed areas ("neg.")



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 11

Example: Etching Step, opening of SiO_2

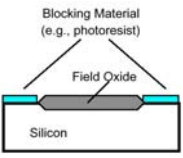


Etching is for removal of material, similar masking principles for deposition (adding of material)

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 12

Oxidation

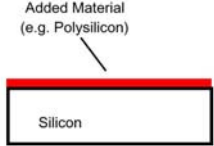
- SiO₂ formed by oxidation
 - Wet oxidation: heat with water (900°C - 1200 °C)
 - Dry oxidation: heat with pure oxygen (1200 °C)
- Oxide occupies more volume
- Alternative: deposition



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 13

Adding Materials

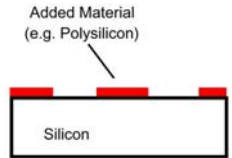
- Add materials on top of silicon
 - Polysilicon
 - Metal
 - SiO₂
- Methods
 - Vapor deposition
 - Sputtering (Metal ions)



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 14

Patterning Added Materials

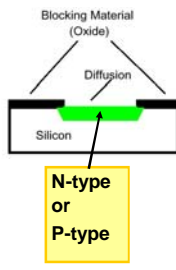
- Add material to wafer
- Coat with photoresist
- Selectively remove photo resist (PR), after exposure through mask
- Remove unprotected (by PR) material
- Remove remaining PR



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 15

Diffusion

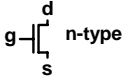
- Modify electrical properties of Si:
 - N-type (extra electrons)
 - or p-type (fewer electrons ↔ extra holes)
- Introduce dopant via ion implant e.g. Arsenic (N), Boron (P) (bombard Si surface with ions)
- Blocking implant in selective areas using oxide or PR (photo-resist)
- Allow dopants to diffuse
- Diffusion spreads both vertically, horizontally



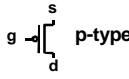
TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 16

CMOS – Complementary Metal Oxide Semiconductor Technology

2 Distinct Transistor Types




n-type



p-type

- “on” when V_g is high
- “on” when V_g is low
- With n-type s/d
- With p-type s/d
- Electrons (n) as carrier
- Holes (p) as carrier
- Built in p-type Si
- Built in n-type Si

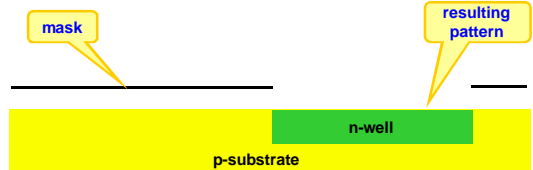


n-well (for PMOS) in p-type substrate (for NMOS)

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 17

Simplified Outline of Process Flow

Place n-well to provide properly-doped substrate for n-type, p-type transistors :



NMOS transistor PMOS transistor

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 18

Outline of Process Flow, cont'd

Pattern **gate** next, to later act as a mask for source and drain diffusions:

NMOS transistor PMOS transistor

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 19

Outline of Process Flow, cont'd

Add **s/d diffusions**, with self-masking by poly gate:

NMOS transistor PMOS transistor

Self-masking: Poly also works as a mask, ensuring good alignment of s/d to gate

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 20

Outline of Process Flow, cont'd

With Field Oxide and Gate Oxide shown

NMOS transistor PMOS transistor

Self-masking: Poly also works as a mask, ensuring good alignment of s/d to gate

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 21

Outline of Process Flow, cont'd

Start adding **metal layers**:

Via: contact hole between metal layers

NMOS transistor PMOS transistor

Similar for subsequent metal layers

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 22

Process Cross-section

8 metal layers

poly (gate) layer

See: Spectrum, IEEE, Volume: 40, Issue: 2, Feb. 2003

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 23

Interconnect Examples (motorola, ibm)

← IBM CMOS 7S copper process, 0.16 μm

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 24

IC Recipe Precisely Fixed

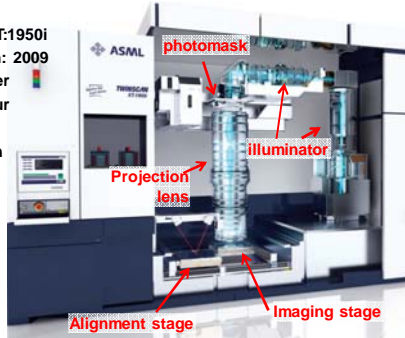
- Process conditions (temperature, time, concentration, ...) **very critical**
- Many **strong compatibility** issues of materials and processes
- Very expensive and **difficult to tune**
- Very expensive **equipment** and facilities
- Need **Billions** of turnover for break-even

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 25

Wafer Stepper (Step and Scan)

ASML Twinscan XT:1950i


- First production: 2009
- 193 nm ArF Laser
- >175 Wafers/Hour
- <2.5 nm overlay
- 32 nm resolution



TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 26

Immersion Lithography

Dual Stage Advantage : Measure Dry - Expose Wet



Immersion Shower Head Integrated Liquid Supply (temp, degassing, purity)

Dry Alignment Dry Wafer Mapping (Focus & Levelling)

No Metrology Sensor Around Lens for easy Shower Head Implementation

ASML


- Water, rather than air between lens and wafer
- Improved imaging because of higher index of refraction
- Alignment stage for mapping height profile of wafer in advance of exposure
- DOF < 1µm

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 27

Compare Stepper Wafer Size and Resolution to NL scale

- Resolution: 32nm
- Wafer size: Ø 300mm
- Netherlands: 40.000 km² ~ Ø 225km

300mm	1	32nm
225km	750x10 ³	2.4cm



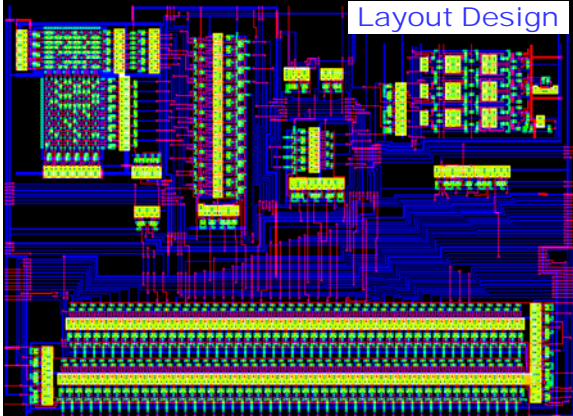
A 'magnified' waferstepper could 'print' the Netherlands with a resolution of 2.4 cm in 21 sec.

Better than 7.7x10⁶ sheets of A4 at 300 dpi ...

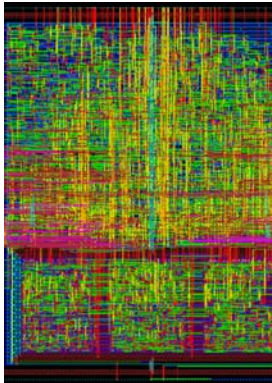
... a pile of paper of 800 m high

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 28

Layout Design

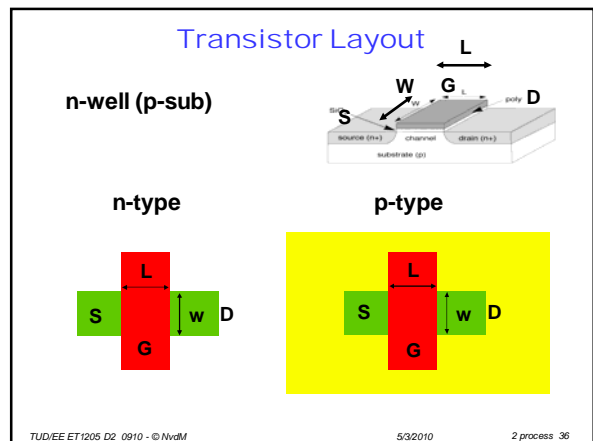
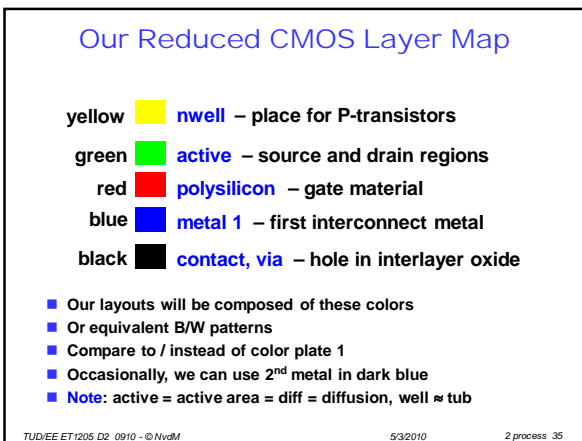
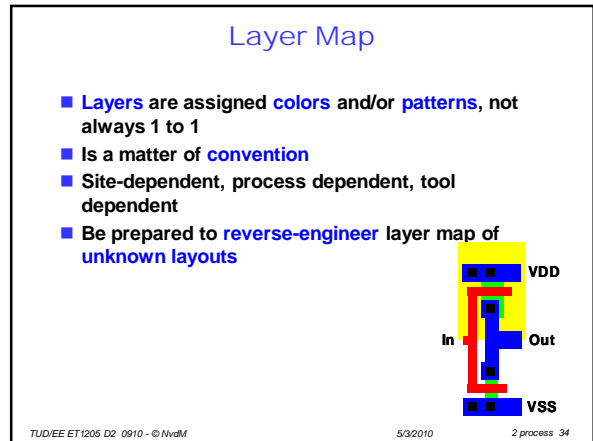
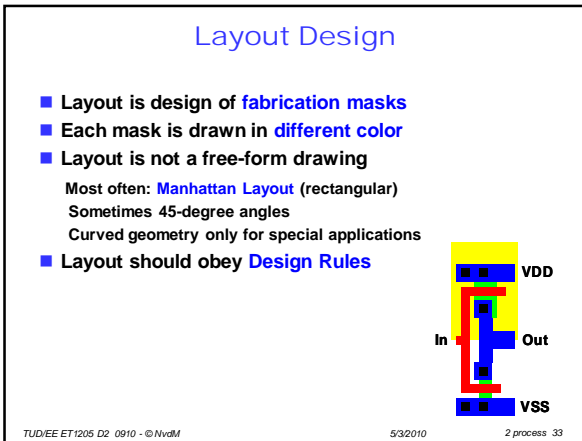
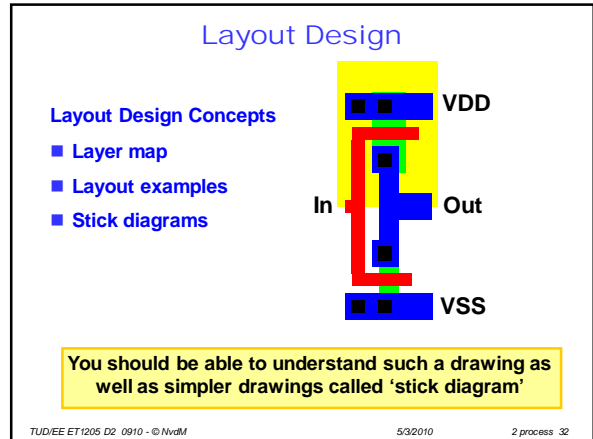
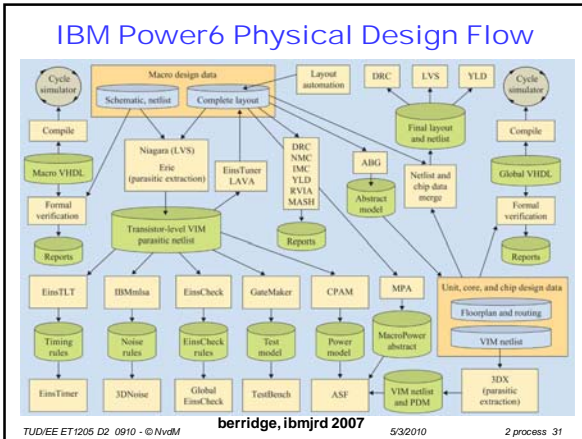


TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 30



- Mostly created by software
- Chip design software is a difficult to tame beast
- But w/o software it is impossible to design a chip

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 30



Polarity of Active Area

- **Active layer** or active area is the source/drain implant layer (area). Usually abbreviated as 'active' only.
- Normally, a so-called **select mask** determines polarity of active
- See color plate 5
- We will implicitly define polarity of active by **n-well**
- Or we will even omit the nwell and use the context

nwell

p+

n+

active

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 37

Contact Holes and Vias

A --- B **Layout (top view)**

metal2
metal 1
poly

Cross-section along A-B

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 38

Inverter Layout

Main difficulty: you need to guess/extrapolate covered portions of the layout (e.g. green under blue)

Given such a layout, you should be able to draw the circuit on the left, as well as the different cross-sections

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 39

From Schematic to Layout

Transistor schematic

Layout

■ Active
■ Poly Si
■ Metal 1
■ Contact

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 40

NAND3_X1 (45nm)

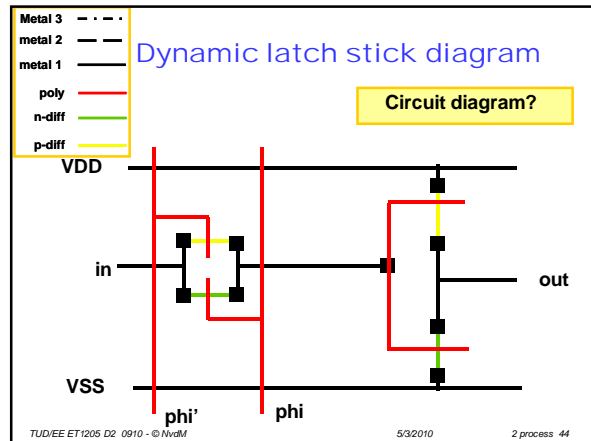
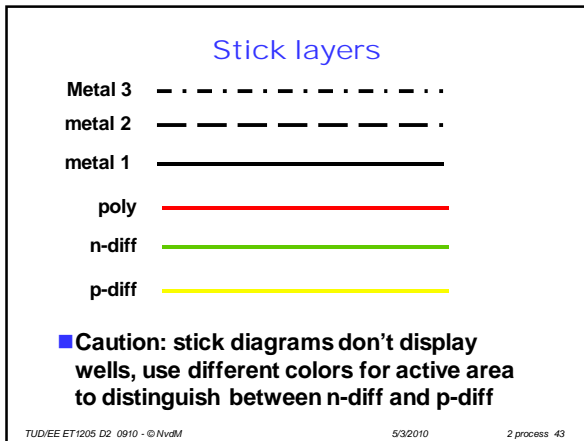
Standard cell:
Fixed pitch and width of VDD and VSS traces

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 41

Stick diagrams

- A stick diagram is a **cartoon** of a layout.
- Does show components/vias but only **relative placement**.
- Does **not** show **exact placement**, transistor sizes, wire lengths, wire widths, tub boundaries, some special components.

TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 42



- ### Design Rules
- The fabrication process will suffer from **tolerances**
 - Chip features will have a practical **minimum size** to allow them to be fabricated reliably enough (with high enough **yield**)
 - This is captured into a set of precise **Design Rules**
 - Modern processes have terribly complex set of design rules as a compromise between **flexibility** and **manufacturability**
 - We will **ignore** this subject
 - But you will have to understand it during **OP** next year.
- TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 45

- ### Summary
- CMOS Processing
 - Photolithography
 - Material Deposition & Removal
 - Oxide Growth & Removal
 - CMOS Process Outline
 - Layout Design
 - Layer map
 - Layout examples
 - Stick diagrams
 - Design Rules
 - Why we need design rules
- TUD/EE ET1205 D2 0910 - © NvdM 5/3/2010 2 process 46